

## General Description

The MAX100 ECL-compatible, 250Msps, 8 -bit analog-todigital converter (ADC) allows accurate digitizing of analog signals from DC to 125 MHz (Nyquist frequency). Designed with Maxim's proprietary advanced bipolar processes, the MAX100 contains a high-performance track/hold (T/H) amplifier and a quantizer in a single ceramic strip-line package.
The innovative design of the internal T/H assures an exceptionally wide input bandwidth of 1.2 GHz and aperture delay uncertainty of less than 2 ps , resulting in a high 6.8 effective bits performance. Special comparator output design and decoding circuitry reduce out-of-sequence code errors. The probability of erroneous codes occurring due to metastable states is reduced to less than 1 error per $10^{15}$ clock cycles. Unlike other ADCs, which can have errors that result in false full-scale or zero-scale outputs, the MAX100 keeps the magnitude to less than 1LSB.
The analog input is designed for either differential or singleended use with a $\pm 270 \mathrm{mV}$ range. Sense pins for the reference input allow full-scale calibration of the input range or facilitate ratiometric use. Midpoint tap for the reference string is available for applications that need to modify the output coding for a user-defined bilinear response. Use of separate high-current and low-current ground pins provides better noise immunity and highest device accuracy.
Dual output data paths provide several data output modes for easy interfacing. These modes can be configured as either one or two identical latched ECL outputs. An 8:16 demultiplexer mode that reduces the output data rates to one-half the clock rate is also available.
For applications that require faster data rates, refer to Maxim's MAX101, which allows conversion rates up to 500Msps.

- 250 Msps Conversion Rate
6.8 Effective Bits at 125 MHz
Less than $\pm 1 / 2 \mathrm{LSB}$ INL
$50 \Omega$ Differential or Single-Ended Inputs
$\pm 270 \mathrm{mV}$ Input Signal Range
Reference Sense Inputs
Ratiometric Reference Inputs
- Configurable Dual-Output Data Paths
Latched, ECL-Compatible Outputs
Low Error Rate, Less than 10-15 Metastable States
- Selectable On-Chip 8:16 Demultiplexer
84-Pin Ceramic Flat Pack

Applications
High-Speed Digital Instrumentation
High-Speed Signal Processing
Medical Systems
Radar/Sonar
High-Energy Physics
Communications
Ordering Information

| PART | TEMP. RANGE | PIN-PACKAGE |
| :---: | :---: | :---: |
| MAX100CFR $^{*}$ | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | 84 Ceramic Flat Pack (with heatsink) |

*Contact factory for 84-Pin Ceramic Flat Pack without heatsink.

Functional Diagram


MAXI/V
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## 250Msps, 8-Bit ADC with Track/Hold

## ABSOLUTE MAXIMUM RATINGS (Note 1)

| ges |  |
| :---: | :---: |
|  |  |
| VCC |  |
| VCC - VEE............................................................12V |  |
| Analog Input Voltage .......................................................................................................................... +0 VDigital Input Voltage |  |
|  |  |
| Digital Input Voltage ................................................................................. to +0 V to +1.5 VReference Voltage (VART) |  |



Note 1: The digital control inputs are diode protected; however, permanent damage may occur on unconnected units under high energy electrostatic fields. Keep unused units in conductive foam or shunt the terminals together. Discharge the conductive foam to the destination socket before insertion.
Note 2: Typical thermal resistance, junction-to-case $R_{\theta J C}=5^{\circ} \mathrm{C} / \mathrm{W}$ and thermal resistance, junction to ambient (MAX100CA) R QJA $=$ $12^{\circ} \mathrm{C} / \mathrm{W}$, providing 200 lineal $\mathrm{ft} / \mathrm{min}$ airflow with heatsink. See Package Information.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

ELECTRICAL CHARACTERISTICS
$\left(\mathrm{V}_{\mathrm{EE}}=-5.2 \mathrm{~V}, \mathrm{~V}_{\mathrm{CC}}=+5 \mathrm{~V}, \mathrm{R}_{\mathrm{L}}=50 \Omega\right.$ to $-2 \mathrm{~V}, \mathrm{VART}=1.02 \mathrm{~V}, \mathrm{VARB}=-1.02 \mathrm{~V}, \mathrm{~T}_{\mathrm{MIN}}$ to $\mathrm{T}_{\mathrm{MAX}}=0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}, \mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$, unless otherwise noted.) (Note 3)

| PARAMETER | SYMBOL | CONDITIONS |  | MIN | TYP | MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| ACCURACY |  |  |  |  |  |  |  |
| Resolution |  |  |  | 8 |  |  | Bits |
| Integral Nonlinearity (Note 4) | INL | AData, BData | $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$ |  |  | $\pm 0.5$ | LSB |
|  |  |  | $\mathrm{T}_{\mathrm{A}}=\mathrm{T}_{\text {MIN }}$ to $\mathrm{T}_{\text {MAX }}$ |  |  | $\pm 0.6$ |  |
| Differential Nonlinearity | DNL | AData, BData, no missing codes | $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$ |  |  | $\pm 0.75$ | LSB |
|  |  |  | $\mathrm{T}_{\mathrm{A}}=\mathrm{T}_{\text {MIN }}$ to $\mathrm{T}_{\text {MAX }}$ |  |  | $\pm 0.85$ |  |
| DYNAMIC SPECIFICATIONS |  |  |  |  |  |  |  |
| Effective Bits | ENOB | $\mathrm{f} C L K=250 \mathrm{MHz}$, <br> $\mathrm{V}_{\mathrm{IN}}=95 \%$ full scale <br> (Note 5) | $\mathrm{f}_{\text {AIN }}=10 \mathrm{MHz}$ |  | 7.4 |  | Bits |
|  |  |  | $\mathrm{f}_{\text {AIN }}=50 \mathrm{MHz}$ |  | 7.1 |  |  |
|  |  |  | $\mathrm{f}_{\text {AIN }}=125 \mathrm{MHz}$ | 6.8 |  |  |  |
| Signal-to-Noise Ratio | SNR | $\begin{aligned} & \mathrm{f}_{\text {AIN }}=50 \mathrm{MHz}, \mathrm{fCLK}=250 \mathrm{MHz}, \mathrm{~V} \text { IN }=95 \% \\ & \text { full scale }(\text { Note } 6) \end{aligned}$ |  | 44.5 |  |  | dB |
| Maximum Conversion Rate | fCLK | (Note 7) |  | 250 |  |  | Msps |
| Analog Input Bandwidth | BW3dB |  |  | 1.2 |  |  | GHz |
| Aperture Width | taw | Figure 5 |  | 270 |  |  | ps |
| Aperture Jitter | tAJ | Figure 5 |  | 2 |  |  | ps |
| ANALOG INPUT |  |  |  |  |  |  |  |
| Input Voltage Range | VIN | $\begin{aligned} & \text { AIN+ to AIN-, Table 2, } \\ & \mathrm{T}_{\mathrm{A}}=\mathrm{T}_{\text {MIN }} \text { to } \mathrm{T}_{\text {MAX }} \end{aligned}$ | Full scale | 230 |  | 315 | mV |
|  |  |  | Zero scale | -305 |  | -215 |  |
| Input Offset Voltage | VIO | AIN+, AIN-, $\mathrm{T}_{\mathrm{A}}=\mathrm{T}_{\text {MIN }}$ to $\mathrm{T}_{\text {MAX }}$ |  | -17 |  | +32 | mV |
| Least-Significant-Bit Size | LSB | $\mathrm{T}_{\mathrm{A}}=\mathrm{T}_{\text {MIN }}$ to $\mathrm{T}_{\text {MAX }}$ |  | 1.8 |  | 2.5 | mV |
| Input Resistance | RI | AIN+ and AIN- with respect to GND |  | 49 |  | 51 | $\Omega$ |
| Input Resistance Temperature Coefficient |  |  |  | 0.008 |  |  | $\Omega /{ }^{\circ} \mathrm{C}$ |

## 250Msps, 8-Bit ADC with Track/Hold

## ELECTRICAL CHARACTERISTICS (continued)

$\left(\mathrm{V}_{\mathrm{EE}}=-5.2 \mathrm{~V}, \mathrm{~V}_{\mathrm{CC}}=+5 \mathrm{~V}, \mathrm{R}_{\mathrm{L}}=50 \Omega\right.$ to $-2 \mathrm{~V}, \mathrm{VART}_{\mathrm{R}}=1.02 \mathrm{~V}, \mathrm{VA} \mathrm{VBB}^{2}=-1.02 \mathrm{~V}, \mathrm{~T}_{\mathrm{MIN}}$ to $\mathrm{T}_{\mathrm{MAX}}=0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}, \mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$, unless otherwise noted.) (Note 3)


## 250Msps, 8-Bit ADC with Track/Hold

## TIMING CHARACTERISTICS

$\left(\mathrm{V}_{\mathrm{EE}}=-5.2 \mathrm{~V}, \mathrm{~V}_{\mathrm{CC}}=+5 \mathrm{~V}, \mathrm{R}_{\mathrm{L}}=50 \Omega\right.$ to $-2 \mathrm{~V}, \mathrm{VA}_{\mathrm{RT}}=1.02 \mathrm{~V}, \mathrm{VA}_{\mathrm{RB}}=-1.02 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$, unless otherwise noted. $)$

| PARAMETER | SYMBOL | CONDITIONS |  |  | MIN | TYP | MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Clock Pulse Width Low | tPWL | CLK, CLK, Figures 1 and 2 |  |  | 1.9 |  | 5.0 | ns |
| Clock Pulse Width High | tPWH | CLK, CLK, Figures 1 and 2 |  |  | 1.9 |  |  | ns |
| CLK to DCLK Propagation Delay | tPD1 | DIV $=0$, Figure 1 |  |  | 0.8 |  | 2.4 | ns |
|  |  | DIV $=1$, Figure 2 |  |  | 1.9 |  | 5.7 |  |
| DCLK to A/BData Propagation Delay | tPD2 | DIV $=0$, Figure 1 |  |  | 0.5 |  | 2.2 |  |
|  |  | DIV $=1$, Figure 2 |  |  | -1.4 |  | -0.1 | s |
| Rise Time | tR | 20\% to 80\% | DCLK |  | 500 |  |  | ps |
|  |  |  | DATA |  |  | 700 |  |  |
| Fall Time | $\mathrm{tF}_{\text {F }}$ | 20\% to 80\% | DCLK |  |  | 600 |  | ps |
|  |  |  | DATA |  |  | 550 |  |  |
| Pipeline Delay (Latency) | tNPD | See Figures 3 and 4 and Table 1 (delay depends on output mode) | Divide-by-1 mode |  | $71 / 2$ |  | $71 / 2$ | Clock Cycles |
|  |  |  | Divide-by2 mode | AData | $71 / 2$ |  | $71 / 2$ |  |
|  |  |  |  | BData | $81 / 2$ |  | $81 / 2$ |  |

Note 3: All devices are $100 \%$ production tested at $+25^{\circ} \mathrm{C}$ and are guaranteed by design for $\mathrm{T}_{\mathrm{A}}=\mathrm{T}_{\text {MIN }}$ to $\mathrm{T}_{\text {MAX }}$ as specified. Note 4: Deviation from best-fit straight line. See Integral Nonlinearity section.
Note 5: See the Signal-to-Noise Ratio and Effective Bits section in the Definitions of Specifications.
Note 6: SNR calculated from effective bits performance using the following equation: SNR $(\mathrm{dB})=1.76+(6.02)$ (effective bits).
Note 7: Clock pulse width minimum requirements tPWL and tpWH must be observed to achieve stated performance.
Note 8: Functionality guaranteed for $-1.07 \leq \mathrm{V}_{\mathrm{IH}} \leq-0.7$ and $-2.0 \leq \mathrm{V}_{\mathrm{IL}} \leq-1.5$.
Note 9: Outputs terminated through $50 \Omega$ to -2.0 V .

Typical Operating Characteristics
( $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$, unless otherwise noted.)


## 250Msps, 8-Bit ADC with Track/Hold



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## 250Msps, 8-Bit ADC with Track/Hold

| PIN | NAME | FUNCTION |
| :---: | :---: | :---: |
| 1 | PAD | Internal connection, leave open. |
| 2, 62 | CLK | Complementary Differential Clock Inputs. Can be driven from standard 10K ECL with the following considerations: Internally, pins $2 \& 62$ and $3 \& 61$ are the ends of a $50 \Omega$ transmission line. Either end can be driven, with the other end terminated with $50 \Omega$ to -2V. See Typical Operating Circuit. |
| 3, 61 | $\overline{\text { CLK }}$ |  |
| $\begin{gathered} 4,7,15,49 \\ 57,60,64, \\ 67,70,71, \\ 74,77,78, \\ 79,82,84 \end{gathered}$ | GND | Power-Supply Ground. Connect GND and DGND pins (Note 10). |
| $\begin{aligned} & 5,6,9,10, \\ & 31,33,35, \\ & 48,58,59, \\ & 63,81,83 \end{aligned}$ | N.C. | No Connect-there is no internal connection to these pins. |
| 8, 21, 43, 56 | VCC | Positive power supply, $+5 \mathrm{~V} \pm 5 \%$ nominal |
| 11 | DIV | Divide Enable Input. DIV and MOD select the output modes. See Table 1. |
| 12 | MOD | Modulus. MOD and DIV select the output modes. See Table 1. |
| 13 | $\overline{\text { DCLK }}$ | Complementary Differential Clock Outputs. Used to synchronize following circuitry: AData and BData outputs are valid tpD2 after the rising edge of DCLK. See Figures 1-4. |
| 14 | DCLK |  |
| 16 | $A=B$ | Sets AData equal to BData when asserted ( $A=B=1$ ). See Table 1. |
| $\begin{gathered} 17,20,23, \\ 26,36,39 \\ 42,45 \end{gathered}$ | A7-A0 | AData and BData Outputs. A0 and B0 are the LSBs, and A7 and B7 are the MSBs. AData and BData outputs conform to standard 10K ECL logic swings and drive $50 \Omega$ transmission lines. Terminate with $50 \Omega$ to -2 V . See Figures 1-4. |
| $\begin{gathered} 19,22,25, \\ 28,38,41 \\ 44,47 \end{gathered}$ | B7-B0 |  |
| $\begin{gathered} 18,24,27, \\ 30,34,37, \\ 40,46 \end{gathered}$ | DGND | Power-Supply Ground. Connect all ground (GND, DGND) pins together, as described in Note 10. |
| 29 | SUB | Circuit Substrate Contact. This pin must be connected to VEE. |
| 32, 69, 80 | VEE | Negative Power Supply, $-5.2 \mathrm{~V} \pm 5 \%$ nominal |
| 50 | VART | Positive Reference Voltage Input (Note 11) |
| 51 | VARTS | Positive Reference Voltage Sense (Note 11) |

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| PIN | NAME |  |
| :---: | :---: | :--- |
| 52 | VACTS | Reference Bias Resistor Center-Tap Sense (Note 12) |
| 53 | VACT | Reference Bias Resistor Center Tap (Note 12) |
| 54 | VARBS $^{\prime 2}$ | Negative Reference Voltage Sense (Note 11) |
| 55 | VARB | Negative Reference Voltage Input (Note 11) |
| 65 | TP3 | Internal node. Do not connect. |
| 66 | TP2 | Internal node. Do not connect. |
| 68 | TP1 | Internal connection. This pin must be connected to GND. |
| 72,73 | AIN+ | Analog Inputs, internally terminated with 50ת to ground. Full-scale linear input range is approximately |
| 75,76 | AIN- | $\pm 270 \mathrm{mV}$. Drive AIN + and AIN- differentially for best high-frequency performance. |

Note 10: Use a multilayer board with a separate layer dedicated to ground. Connect GND and DGND in separate areas in the ground plane (separated by at least $1 / 4 \mathrm{inch}$ ) and at only one location on the board (see Typical Operating Circuit).
Note 11: Reference bias supply. Use a separate high-quality supply for these pins. Carefully bypassing these pins to achieve noise-free operation of the reference supplies contributes directly to high ADC accuracy.
Note 12: The center-tap connection of the MAX100 is normally left open. It can be driven with a bias voltage, but should be bypassed carefully (refer to Note 11)


Figure 1. Output Timing: Divide-by-1 Mode (DIV = 0)

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OOLXVW

Figure 2. Output Timing: Divide-by-2 or Divide-by-5 Mode (DIV = 1)


Figure 3. Output Timing: Clock to Data, Divide-by-1 Mode (fast mode, DIV = 0)


Figure 4. Output Timing: Divide-by-2 Mode (DIV = 1)

## 250Msps, 8-Bit ADC with Track/Hold

## Definitions of Specifications

Signal-to-Noise Ratio and Effective Bits Signal-to-noise ratio (SNR) is the ratio between the RMS amplitude of the fundamental input frequency and the RMS amplitude of all other analog-to-digital (A/D) output signals. The theoretical minimum A/D noise is caused by quantization error and is a direct result of the ADC's resolution: $\mathrm{SNR}=(6.02 \mathrm{~N}+1.76) \mathrm{dB}$, where N is the number of effective bits of resolution. Therefore, a perfect 8 -bit ADC can do no better than 50 dB . The FFT plots in the Typical Operating Characteristics show the output level in various spectral bands.
Effective bits is calculated from a digital record taken from the ADC under test. The quantization error of the ideal converter equals the total error of the device. In addition to ideal quantization error, other sources of error include all DC and AC nonlinearities, clock and aperture jitter, missing output codes, and noise. Noise on references and supplies also degrades effective bits performance.
The ADC's input is a sine wave filtered with an anti-aliasing filter to remove any harmonic content. The digital record taken from this signal is compared against a mathematically generated sine wave. DC offsets, phase, and amplitudes of the mathematical model are adjusted until a best-fit sine wave is found. After subtracting this sine wave from the digital record, the residual error remains. The rms value of the error is applied in the following equation to yield the ADC's effective bits.

$$
\text { Effective bits }=N-\log _{2}\left(\frac{\text { measured rms error }}{\text { ideal rms error }}\right)
$$

where N is the resolution of the converter. In this case, $\mathrm{N}=8$.
The worst-case error for any device will be at the converter's maximum clock rate with the analog input near the Nyquist rate ( $1 / 2$ the input clock rate)

## Aperture Width and J itter

Aperture width is the time the T/H circuit takes to disconnect the hold capacitor from the input circuit (i.e., to turn off the sampling bridge and put the T/H in hold mode). Aperture jitter is the sample-to-sample variation in aperture delay (Figure 5).

## Error Rates

Errors resulting from metastable states may occur when the analog input voltage, at the time the sample is taken, falls close to the decision point for any one of the input comparators. The resulting output code for many


Figure 5. T/H Aperture Timing
typical converters can be incorrect, including false fullor zero-scale output. The MAX100's unique design reduces the magnitude of this type of error to 1LSB, and reduces the probability of the error occurring to less than one in every $10^{15}$ clock cycles. If the MAX100 were operated at $250 \mathrm{MHz}, 24$ hours a day, this would translate to less than one metastable-state error every 46 days.

Integral Nonlinearity
Integral nonlinearity (INL) is the deviation of the transfer function from a reference line measured in fractions of 1LSB using a "best straight line" determined by a least square curve fit.

## Differential Nonlinearity

Differential nonlinearity (DNL) is the difference between the measured LSB step and an ideal LSB step size between adjacent code transitions. DNL is expressed in LSBs and is calculated using the following equation:

$$
\mathrm{DNL}(\mathrm{LSB})=\frac{[\text { VMEAS }-(\text { VMEAS-1 })]-\text { LSB }}{\text { LSB }}
$$

where $\mathrm{V}_{\text {MEAS }} 1$ is the measured value of the previous code.
A DNL specification of less than 1LSB guarantees no missing codes and a monotonic transfer function.

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## Detailed Description

Converter Operation
The parallel or "flash" architecture used by the MAX100 provides the fastest multibit conversion of all common integrated ADC designs. The basic element of a flash (as with all other ADC architectures) is the comparator, which has a positive input, a negative input, and an output. If the voltage at the positive input is higher than the negative input (connected to a reference), the output will be high. If the positive input voltage is lower than the reference, the output will be low. A typical $n$ bit flash consists of $2^{n}-1$ comparators with negative inputs evenly spaced at 1LSB increments from the bottom to the top of the reference ladder. For $n=8$, there will be 255 comparators.
For any input voltage, all the comparators with negative inputs connected to the reference ladder below the input voltage will have outputs of 1, and all comparators with negative inputs above the input voltage will have outputs of 0 . Decode logic is provided to convert this information into a parallel n -bit digital word (the output) corresponding to the number of LSBs (minus 1) that the input voltage is above the level set at the bottom of the ladder.
Finally, the comparators contain latch circuitry and are clocked. This allows the comparators to function as described above when, for example, clock is low. When clock goes high (samples) the comparator will latch and hold its state until the clock goes low again.

Track/Hold
As with all ADCs, if the input waveform is changing rapidly during the conversion the effective bits and SNR will decrease. The MAX100 has an internal track/hold (T/H) that increases attainable effective-bits performance and allows more accurate capture of analog data at high conversion rates.
The internal T/H circuit provides two important circuit functions for the MAX100:

1) Its nominal voltage gain of 4 reduces the input driving signal to $\pm 270 \mathrm{mV}$ differential (assuming a $\pm 1.02 \mathrm{~V}$ reference).
2) It provides a differential $50 \Omega$ input that allows easy interface to the MAX100.

Data Flow
The MAX100 contains an internal T/H amplifier that stores the analog input voltage for the ADC to convert. The differential inputs AIN+ and AIN- are tracked continuously between data samples. When a negative CLK edge is applied, the T/H enters hold mode (Figure 5).

When CLK goes low, the most recent sample is presented to the ADC's input comparators. Internal processing of the sampled data is delayed for several clock cycles before it is available at outputs AData or BData. All output data is timed with respect to DCLK and DCLK (Figures 1-4).

## Applications Information

## Analog Input Ranges

Although the normal operating range is $\pm 270 \mathrm{mV}$, the MAX100 can be operated with up to $\pm 500 \mathrm{mV}$ on each input with respect to ground. This extended input level includes the analog signal and any DC common-mode voltage.
To obtain a full-scale digital output with differential input drive, a nominal +270 mV must be applied between AIN + and AIN-. That is, AIN+ $=+135 \mathrm{mV}$ and AIN- $=$ -135 mV (with no DC offset). Mid-scale digital output code occurs when there is no voltage difference across the analog inputs. Zero-scale digital output code, with differential -270 mV drive, occurs when AIN $+=-135 \mathrm{mV}$ and AIN- $=+135 \mathrm{mV}$. Table 2 shows how the output of the converter stays at all ones (full scale) when over ranged or all zeros (zero scale) when under ranged.
For single-ended operation:

1) Apply a DC offset to one of the analog inputs, or leave one input open. (Both AIN+ and AIN- are terminated internally with $50 \Omega$ to analog ground.)
2) Drive the other input with a $\pm 270 \mathrm{mV}+$ offset to obtain either full- or zero-scale digital output. If a DC common-mode offset is used, the total voltage swing allowed is $\pm 500 \mathrm{mV}$ (analog signal plus offset with respect to ground).

Table 1. Input Voltage Range

| INPUT | AIN+** <br> $(\mathbf{m V})$ | AIN-** <br> $(\mathbf{m V})$ | OUTPUT <br> CODE | MSB to LSB |
| :--- | :---: | :---: | :---: | :--- |
| Differential | +135 | -135 | 1111111 | full scale |
|  | 0 | 0 | 10000000 | mid scale |
|  | -135 | +135 | 00000000 | zero scale |
| Single <br> Ended | +270 | 0 | 1111111 | full scale |
|  | 0 | 0 | 10000000 | mid scale |
|  | -270 | 0 | 0000000 | zero scale |

**An offset $\mathrm{V}_{\mathrm{IO}}$, as specified in the DC electrical parameters, may be present at the input. Compensate for this offset by either adjusting the reference voltage (VART or VARB), or introducing an offset voltage in one of the input terminals AIN + or AIN-.

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MAX100
Table 2. Output Mode Control

| DIV | MOD | $A=B$ | $\begin{aligned} & \text { DCLK }^{*} \\ & (\mathrm{MHz}) \end{aligned}$ | MODE | DESCRIPTION |
| :---: | :---: | :---: | :---: | :---: | :---: |
| 0 | X | 0 | 250 | Divide by 1 | Data appears on AData only, BData port inactive (Figure 3). |
| 0 | X | 1 | 250 | Divide by 1 | AData identical to BData (Figure 3). |
| 1 | 0 | 0 | 125 | Divide by 2 | 8:16 demultiplexer mode. AData and BData ports are active. BData carries older sample and AData carries most recent sample (Figure 4). |
| 1 | 0 | 1 | 125 | Divide by 2 | AData and BData ports are active, both carry identical sampled data. Alternate samples are taken but discarded. |
| 1 | 1 | 0 | 50 | Divide by 5 | AData port updates data on 5th input CLK. BData port inactive. Other 4 sampled data points are discarded. |
| 1 | 1 | 1 | 50 | Divide by 5 | AData and BData ports are both active with identical data. Data is updated on output ports every 5th input clock (CLK). The other 4 samples are discarded. |

*Input clocks $(C L K, ~ C L K) ~=250 \mathrm{MHz}$ for all above combinations. In divide-by-2 or divide-by-5 mode the output clock DCLK will always be a $50 \%$ duty-cycle signal. In divide-by-1 mode DCLK will have the same duty cycle as CLK.


Figure 6. Reference Ladder String

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#### Abstract

Reference The ADC's reference resistor is a Kelvin-sensed, centertapped resistor string that sets the ADC's LSB size and dynamic operating range. Normally, the top and bottom of this string are driven with an op amp, and the center tap is left open. However, driving the center tap is an effective way to modify the output coding to provide a user-defined bilinear response. The buffer amplifier used to drive the top and bottom inputs will need to supply approximately 18 mA due to the resistor string impedance of $116 \Omega$ minimum. A reference voltage of $\pm 1.02 \mathrm{~V}$ is normally applied to inputs VART and VArb. This reference voltage can be adjusted up to $\pm 1.4 \mathrm{~V}$ to accommodate extended input requirements (accuracy specifications are guaranteed with $\pm 1.02 \mathrm{~V}$ references). The reference input VArts, VArBS, and VACTs allow Kelvin sensing of the applied voltages to increase precision. An RC network at the ADC's reference terminals is needed for best performance. This network consists of a $33 \Omega$ resistor connected in series with the op amp output that drives the reference. A $0.47 \mu \mathrm{~F}$ capacitor must be connected near the resistor at the op amp's output (see Typical Operating Circuit). This resistor and capacitor combination should be located within 0.5 inches of the MAX100 package. Any noise on these pins will directly affect the code uncertainty and degrade the ADC's effective-bits performance.


CLK and DCLK
All input and output clock signals are differential. The input clocks, CLK and CLK, are the primary timing signals for the MAX100. CLK and CLK are fed to the internal circuitry from pins $2 \& 3$ or pins 62 \& 61 through an internal $50 \Omega$ transmission line. One pair of CLK/CLK inputs should be driven and the other pair terminated by $50 \Omega$ to -2 V . Either pair can be used as the driven inputs (input lines are balanced) for easy circuit connection. A minimum pulse width (tPWL) is required for CLK and CLK (Figures 1-4).
For best performance and consistent results, use a low phase-jitter clock source for CLK and CLK. Phase jitter larger than 2ps from the input clock source reduces the converter's effective-bits performance and causes inconsistent results.

DCLK and $\overline{\text { DCLK }}$ are output clock signals derived from the input clocks and are used for external timing of the AData and BData outputs. The MAX100 is characterized to work with maximum input clock frequencies of 250 MHz (Table 1). See Typical Operating Circuit.

Output Mode Control
DIV, MOD, and $A=B$ are input pins that determine the operating mode of the two output data paths. Six options are available (Table 1). A typical operating configuration ( $8: 16$ demultiplexer mode) is set by 1 on DIV, 0 on MOD, and 0 on $A=B$. This will give the most recent sample at AData with the older data on BData. Both outputs are synchronous and are at half the input clock rate. To terminate the control inputs, use a resistor to -2 V or the equivalent circuit resistor combination from DGND to -5.2 V up to $1 \mathrm{k} \Omega$. When using a diode pull-up to tie an input high, bias the diode "on" with a pull-down resistor to avoid input voltage excursions close to ground. The control inputs are compatible with standard ECL 10K logic levels over temperature.

Layout, Grounding, and Power Supplies The MAX100 is designed with separate analog and digital ground connections to isolate high-current digital noise spikes. The high-current digital ground, DGND, is connected to the collectors of the output emitter follower transistors. The low-current ground connection is GND, which is a combination of the analog ground and the ground of the low-current digital decode section. The DGND and GND connections should be at the same DC level, and should be connected at only one location on the board. This will provide better noise immunity and highest device accuracy. A ground plane is recommended.
$\mathrm{A}+5 \mathrm{~V} \pm 5 \%$ supply as well as a $-5.2 \mathrm{~V} \pm 5 \%$ supply is needed for proper operation. Bypass the VEE and VCC supply pins to GND with high-quality $0.1 \mu \mathrm{~F}$ and $0.001 \mu \mathrm{~F}$ ceramic capacitors located as close to the package as possible. An evaluation kit with a suggested layout is available.

## 250Msps, 8-Bit ADC with Track/Hold

## MAX100



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